Microscopy of Phase Spread Alloy Thin Films



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1 Introduction:

✤The Phase Spread Alloy (PSA) method produces thin films with well-controlled compositional gradients.

This is an efficient way to screen multiple compounds and structural phases for superconductivity on one sample

♦ We use local and non-local probes to verify the presence and distribution of these phases on one sample

✤The La-Si-C system was chosen for its structural resemblance to high T_c superconductors

⁽²⁾PSA: Confocal Sputtering System

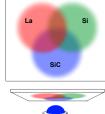
Three sputtering

substrate (Si or sapphire) resulting in

concentration

targets are aimed at a

gradients of element



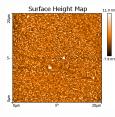


☆ X-ray diffraction shows peaks from the La₅Si₃ phase, along with unindexed peaks from other phases

S superior statements

Performed by the Schuller group at UCSD

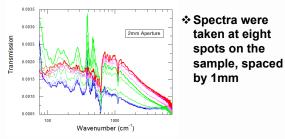
4 Atomic Force Microscopy



♦ RMS roughness of 3.4 nm over an area of 20×20µm

 Roughness is comparable to La films made with the same system with only one gun firing

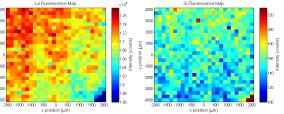
5 Infrared Spectroscopy



Changes at low wavenumber indicate differences in optical conductivity

The Basov group has also developed a scanning probe near-field IR spectroscopy method which can map the optical conductivity of a film with spatial resolution of down to 20nm
Performed by the Basov group at UCSD

⁽³⁾X-Ray Fluorescence Maps



- Micro-fluorescence scans showing the La and Si signals from one sample (Si substrate). Xray beam spot size is 100×100μm.
- Beamline 2-ID-D is capable of focusing beam to 200nm×700nm and can also perform microdiffraction

Performed by the Shpyrko group at beamline 2-ID-D at the Advanced Photon Source at Argonne Nat'l Lab

Conclusions:

6)

***XRD** shows multiple phases present

✤Fluorescence shows the gradient in element concentration

IR spectroscopy shows variation in the optical conductivity of different spots on the sample

♦With multiple characterization tools at our disposal, we can thoroughly analyze the composition of PSA thin films and, when found, pinpoint the phase contributing to superconductivity

Performed by the Shpyrko group at UCSD